

Supplementary data

The Role of Zn Substitution in Improving the Electrical Properties of CuI Thin Films and Optoelectronic Performance of CuI MSM Photodetectors

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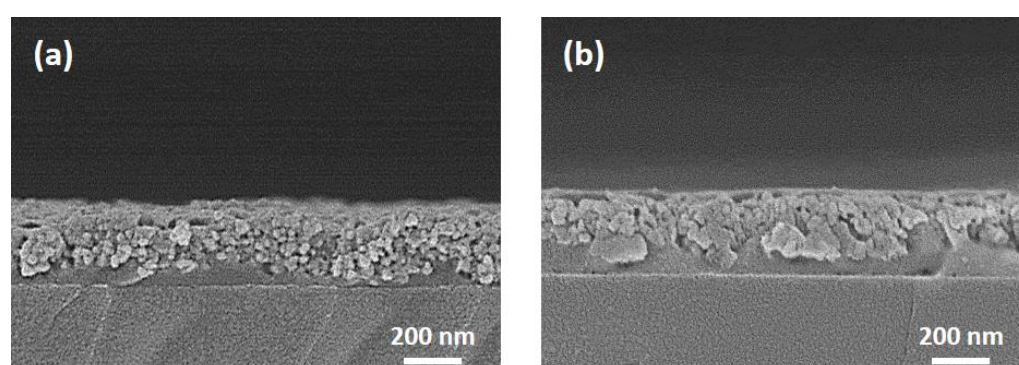


Figure S1. Cross-sectional view FE-SEM micrographs of the pure CuI (a) and 8 at% Zn (b) substituted CuI thin films on glass substrate.

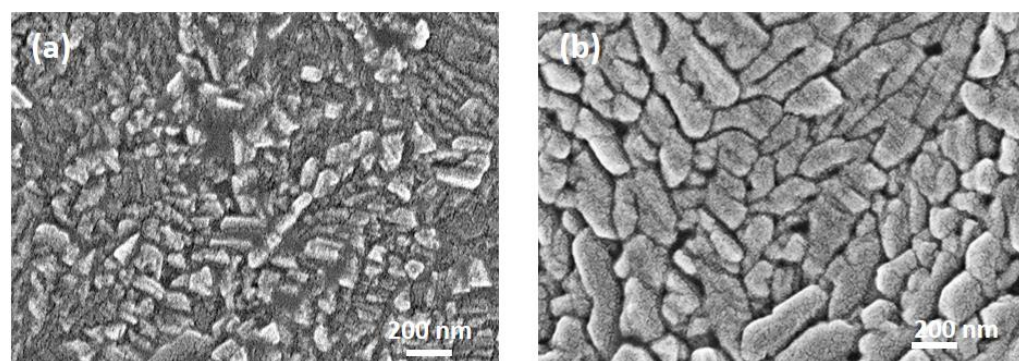


Figure S2. Plane-view FE-SEM micrographs of the pure CuI (a) and 8 at% Zn (b) substituted CuI thin films.

